

Search Notes

Application/Control No.

10/754,572

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

HONG ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	E29.151, E51.005, 72 & 208	12/25/2007	C.C.
257	765	12/25/2007	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; and IBM_TDB;	12/25/2007	C.C.
Considered the references cited in the U. S. Pat. No. 6,696,324	12/25/2007	c.c.